Special Issue

Optical Measurement: Advanced Techniques and Applications

Message from the Guest Editor

This Special Issue welcomes contributions on theoretical advances in, experimental demonstrations of, and applications of advanced optical metrology. Topics of interest include (but are not limited to) the following:

- Interferometry, dynamic interferometry, and frequency-scanning interferometry for continuous/dynamic measurement;
- Deflectometry and slope-based optical testing;
- Fringe projection profilometry for 3D analysis;
- Talbot interferometry and self-imaging wavefront sensing;
- Metrology of freeform and aspheric optical surfaces;
- Phase retrieval and unwrapping algorithms under noisy or dynamic conditions;
- Artificial intelligence and machine learning applications in optical measurement—denoising, adaptive systems, and real-time reconstruction;
- Industrial, biomedical, and manufacturing applications of advanced optical measurement.

Guest Editor

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal *Applied Sciences* has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

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